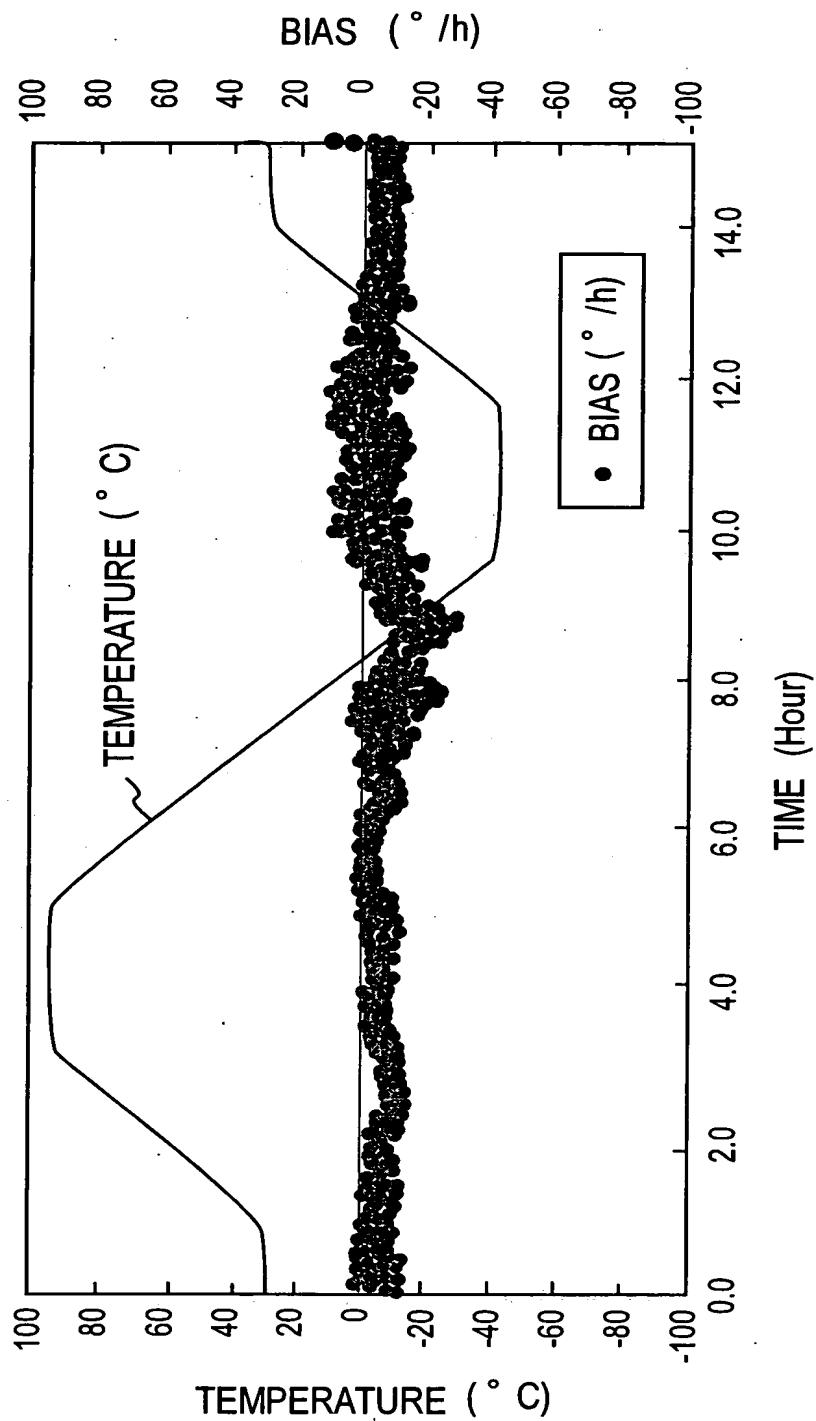


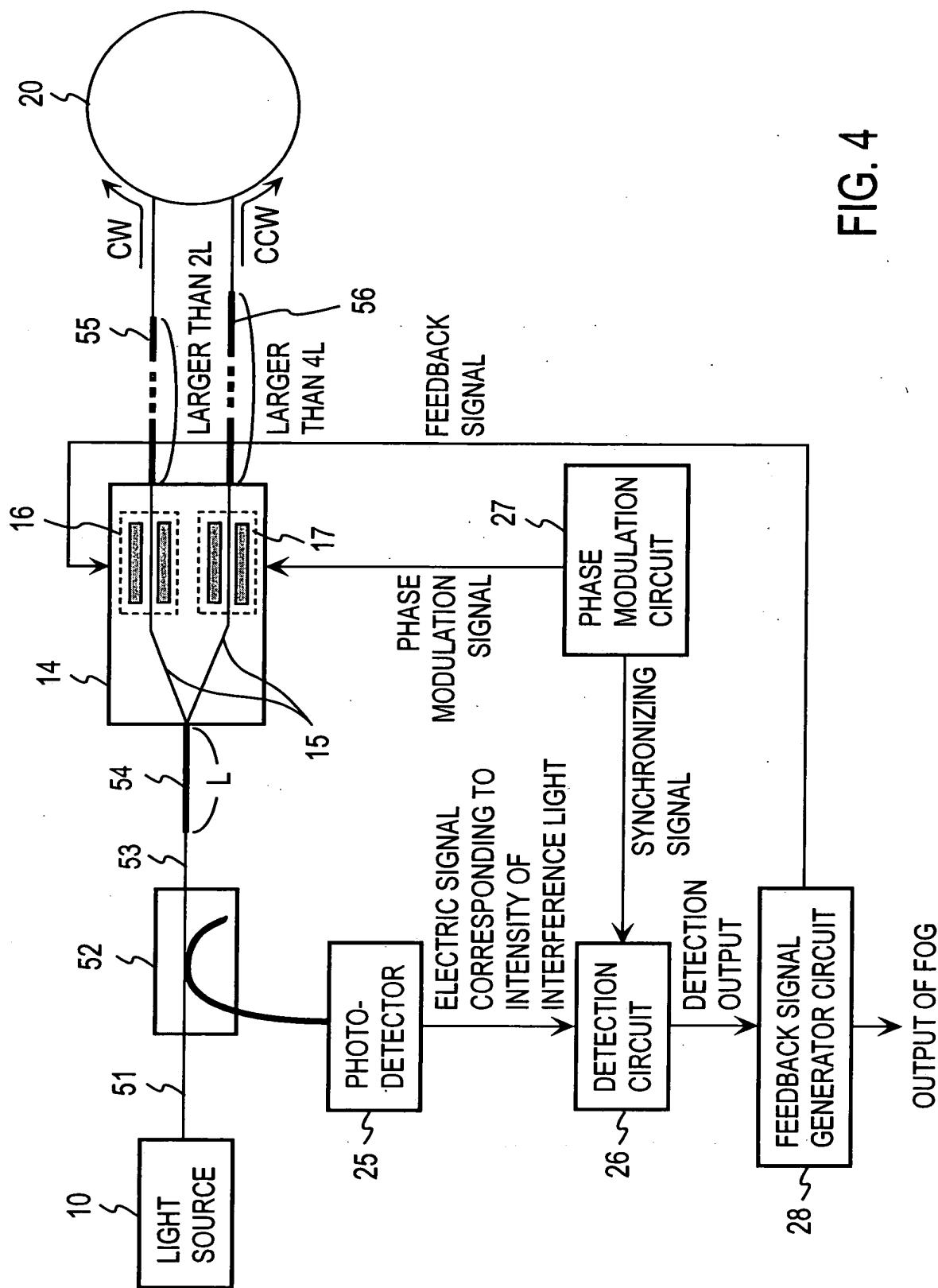
TEMPERATURE TEST IN CASE OPTICAL PATH FROM LIGHT SOURCE TO OPTICAL
INTEGRATED CIRCUIT IS FORMED BY SINGLE MODE OPTICAL FIBER

FIG. 2



TEMPERATURE TEST IN CASE ALL OF OPTICAL PATH FROM LIGHT SOURCE TO
OPTICAL INTEGRATED CIRCUIT IS FORMED BY POLARIZATION MAINTAINING
OPTICAL FIBER

FIG. 3



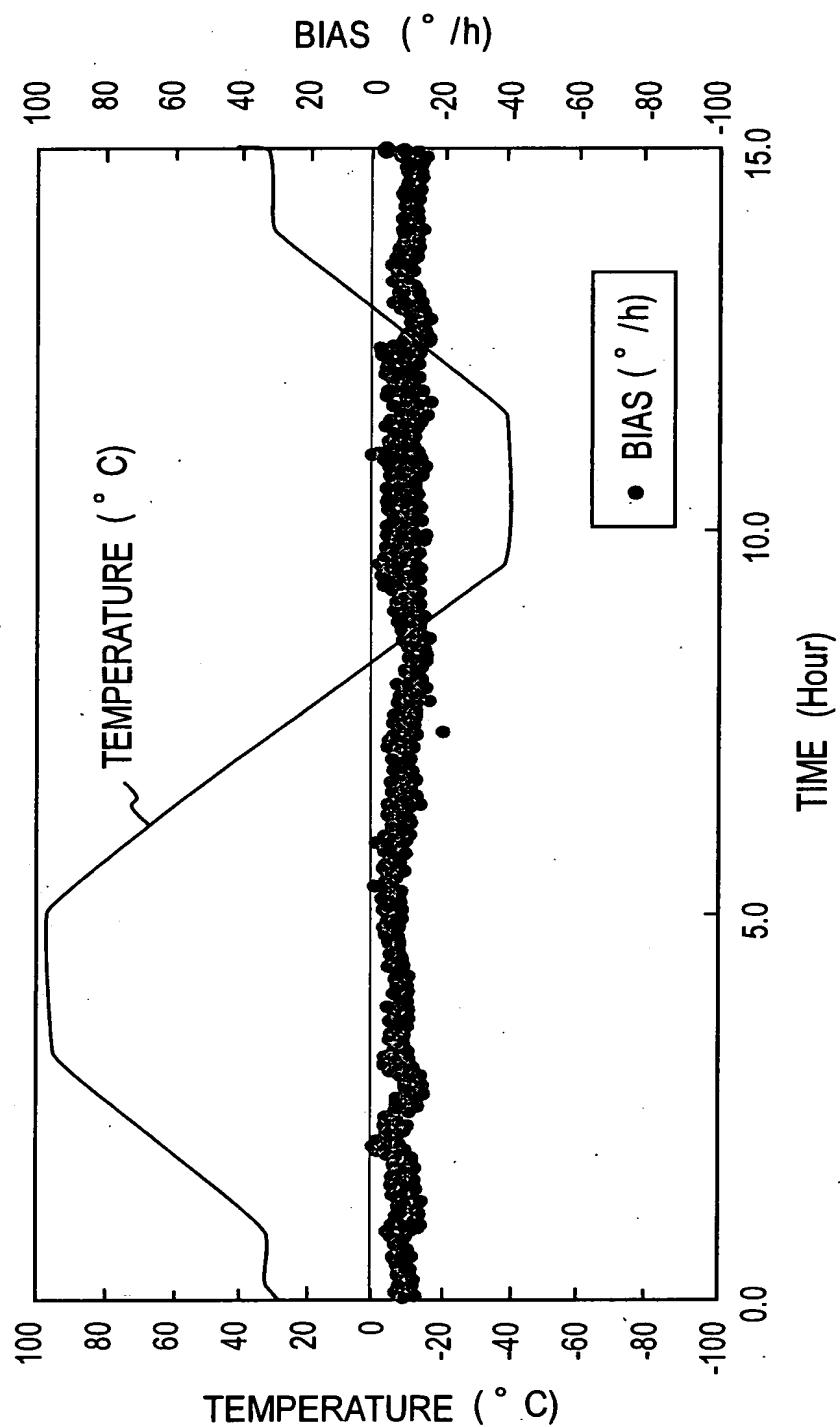
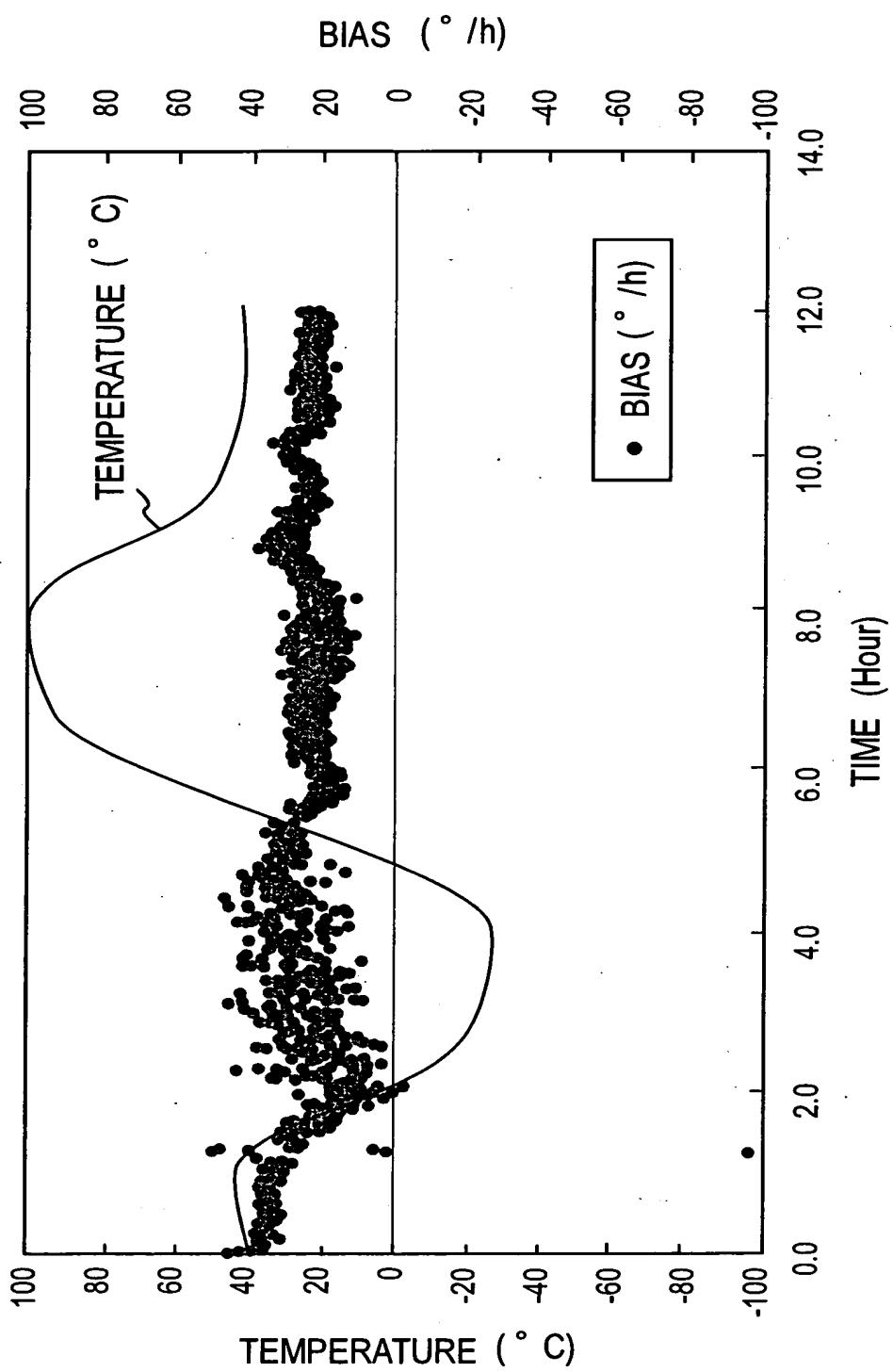


FIG. 5



TEMPERATURE TEST IN CASE A PORTION OF OPTICAL PATH
FROM LIGHT SOURCE TO OPTICAL INTEGRATED CIRCUIT IS
FORMED BY POLARIZATION MAINTAINING OPTICAL FIBER
OF INSUFFICIENT SHORT LENGTH

FIG. 6